3A

3Z [] 2

DW PACKAGE (TOP VIEW)

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24 🛿 2LB

23 🛛 2Z

- Meets or Exceeds the Requirements of ANSI EIA/TIA-232-E and ITU Recommendation V.28
- Four Independent Drivers and Receivers
- Loopback Mode Functionally Self-Tests Drivers and Receivers Without Disconnection From Line
- Driver Slew Rate Limited to 30 V/µs Max
- Built-In Receiver 1-µs Noise Filter
- Internal Thermal Overload Protection
- EIA/TIA-232-E Inputs and Outputs Withstand ±30 V
- Low Supply Current . . . 2.5 mA Typ
- ESD Protection Exceeds 4000 V Per MIL-STD-833C Method 3015

### description

The SN75186 is a low-power bipolar device containing four driver/receiver pairs designed to interface data terminal equipment (DTE) with data circuit-terminating equipment (DCE). Additionally, the SN75186 has a loopback mode that can be used by a data communication system to perform a functional self-test on each driver/receiver pair, removing the need to locally disconnect cables and install a loopback connector. Flexibility of control is ensured by each driver/receiver pair having its own loopback control input. The SN75186 is designed to conform to standards ANSI EIA/TIA-232-E and ITU Recommendation V.28.

The maximum slew rate is limited to 30 V/ $\mu$ s at

the driver outputs, and the SN75186 drives a capacitive load of 2500 pF at 20 kBaud. The receivers have input filters that disregard input noise pulses shorter than 1  $\mu$ s. The SN75186 is a robust device capable of withstanding  $\pm$ 30 V at driver outputs and at receiver inputs whether powered or unpowered. This device has an internal ESD protection rated at 4 kV to prevent functional failures.

The SN75186 is characterized for operation from 0°C to 70°C.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



3LB   4A   4LB   VEE   GND   4B   4Y   3B   3Y	3 4 5 6 7 8 9 10 11 12	22 24 21 1L 20 1Z 19 1A 18 7C 17 7 16 1Y 15 1B 14 2Y 13 2B	B :C2 :C1	
L C C C C C C C C C C C C C C C C C C C	<b>N PAC</b> <b>TOP V</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b> <b>OCO</b>		23 23 22 21 20 19 19 19 19	1Y 1B 2Y 2B 3Y 3B 4Y



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### **Function Tables**

EACH RECEIVER									
LOOPBACK	INP	UTS	INPUT						
LB	Α	в†	DE						
Н	Х	Н	L						
н	Х	L	Н						
L	L	Х	L						
L	Н	Х	н						

#### EACH DRIVER

LOOPBACK LB	INPUT A	о <b></b> трит ү†
Н	Н	L
Н	L	н
L	Х	L

<sup>†</sup> Voltages are EIA/TIA-232-E, and V.28 levels H = high level, L = low level, X = irrelevant

# logic symbol<sup>‡</sup>



<sup>‡</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the DW package.

# POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

# logic diagram, each driver/receiver pair (positive logic)





### schematics of inputs and outputs

All component values shown are nominal.



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>CC1</sub> (see Note 1)	15 V
Supply voltage, V <sub>CC2</sub>	
Supply voltage, V <sub>EE</sub>	–15 V
Receiver input voltage range, V <sub>1</sub>	30 V to 30 V
Driver input voltage range, V <sub>1</sub>	$\dots \dots (V_{EE} + 2 V)$ to $V_{CC1}$
Loopback input voltage range, V <sub>1</sub>	0 V to 7 V
Driver output voltage range, V <sub>O</sub>	30 V to 30 V
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range, T <sub>sto</sub>	–65°C to 150°C
Case temperature for 10 seconds: FN package	260°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: DW package	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltages are with respect to the network ground terminal.

### DISSIPATION RATING TABLE

PACKAGE	T <sub>A</sub> ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING
DW	1350 mW	10.8 mW/°C	864 mW
FN	1400 mW	11.2 mW/°C	896 mW

### recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC1</sub>		10.8	12	13.2	V
Supply voltage, V <sub>CC2</sub>		4.5	5	5.5	V
Supply voltage, VEE		-10.8	-12	-13.2	V
Input voltage, VI	Driver and loopback	0		V <sub>CC2</sub>	V
Input voltage, VI (see Note 2)	Receiver			±30	V
High-level input voltage, VIH	Driver and loopback	2			V
Low-level input voltage, VIL	Driver and loopback			0.8	V
Output voltage powered on or off, VO	Driver			±30	V
High-level output current, IOH	Receiver			-4	mA
Low-level output current, IOL	Receiver			4	mA
Operating free-air temperature, T <sub>A</sub>		0		70	°C

NOTE 2: If all receiver inputs are held at ±30 V, the thermal dissipation limit of the package may be exceeded. The thermal shutdown may not protect the device, as this dissipation occurs in the receiver input resistors.



### **DRIVER SECTION**

# electrical characteristics over full recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS			MIN	TYP†	MAX	UNIT
VOH	High-level output voltage	$R_L = 3 k\Omega$ ,	V <sub>IL</sub> = 0.8 V,	See Figure 1	7			V
VOL	Low-level output voltage <sup>‡</sup>	$R_L = 3 k\Omega$ ,	V <sub>IH</sub> = 2 V,	See Figure 1			-7	V
V <sub>OH(LB)</sub>	High-level output voltage in loopback mode <sup>द</sup>	$R_L = 3 k\Omega$ ,	LB at 0.8 V,	V <sub>IL</sub> = 0.8 V			-7	V
Iн	High-level input current (driver and loopback inputs) <sup>#</sup>	V <sub>I</sub> = 5 V,	See Figure 2				100	μΑ
IIL	Low-level input current (driver and loopback inputs) <sup>#</sup>						-100	μΑ
V <sub>OS(H)</sub>	High-level short-circuit output current	V <sub>I</sub> = 0.8 V,	$V_{O} = 0,$	See Note 3 and Figure 1	-10	-20	-35	mA
V <sub>OS(L)</sub>	Low-level short-circuit output current	V <sub>I</sub> = 2 V,	$V_{O} = 0,$	See Note 3 and Figure 1	10	20	35	mA
ICC1	Supply current from V <sub>CC1</sub>	No load				2.5	4	mA
ICC1(LB)	Supply current from V <sub>CC1</sub> with loopback on	No load,	LB at 0.8 V				10	mA
IEE	Supply current from VEE	No load				-2.5	-4	mA
IEE(LB)	Supply current from V <sub>EE</sub> with loopback on	No load,	LB at 0.8 V				-10	mA
ICC2	Supply current from V <sub>CC2</sub>	No load,	$V_{I} = 0,$	See Note 5		-10	-100	μΑ
ICC2(LB)	Supply current from V <sub>CC2</sub> with loopback on	No load, See Note 5	LB at 0.8 V,	V <sub>I</sub> = 0,		-10	-100	μA
r <sub>o</sub>	Output resistance	V <sub>CC1</sub> = V <sub>EE</sub> See Note 4	$= V_{CC2} = 0,$	$V_{O} = -2 V$ to 2 V,	0.3	5		kΩ

<sup>†</sup> All typical values are at  $T_A = 25^{\circ}C$ .

<sup>‡</sup> The algebraic convention, where the more positive (less negative) limit is designated as maximum, is used in this data sheet for logic levels only. § This is the most positive level to which the driver output rises when the device is in the loopback mode and the driver input is at a low level.

The loopback mode should be entered only when the driver output is in the low (marking) state.

<sup>#</sup> Unused driver inputs should be tied to 0 V or  $V_{CC2}$ , unused loopback inputs should be tied to  $V_{CC2}$ .

NOTES: 3. Minimum I<sub>OS(H)</sub> and I<sub>OS(L)</sub> are specified at V<sub>O</sub>=0, as this more accurately describes the output current needed to dynamically drive capacitive lines. A minimum of ±10 mA is sufficient to drive 2500 pF in parallel with 3 kΩ at a slew rate of 4 V/µs ( in accordance with EIA/TIA-232-E and V.28).

4. Test conditions are those specified by EIA/TIA-232-E.

 Without a load and V<sub>I</sub> = 0, the worst-case conditions, V<sub>CC2</sub> sources a small current originating from V<sub>CC1</sub> giving I<sub>CC2</sub> supply current a negative sign. When a receiver has an output load, V<sub>CC2</sub> sinks static and dynamic supply currents to meet load requirements.



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# switching characteristics over full recommended ranges of supply voltages and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST (	CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low- to high-level output	$R_L = 3 k\Omega$ to 7 kΩ,	CL = 15 pF,		0.6	5	μs
<sup>t</sup> PHL	Propagation delay time, high- to low-level output	See Figure 3			0.8	5	μs
<sup>t</sup> sk	tPLH - tPHL	$R_L = 3 k\Omega$ to 7 k $\Omega$ ,	$C_L = 15 \text{ pF}$ to 2500 pF		0.2	1	μs
SR	Output slew rate	$R_{L}$ = 3 k $\Omega$ to 7 k $\Omega$ ,	$C_L = 15 \text{ pF} \text{ to } 2500 \text{ pF}$	4		30	V/µs
<sup>t</sup> pd(ILB)	Propagation delay time going into loopback mode <sup>‡</sup>	$R_L = 3 k\Omega$ to 7 k $\Omega$ ,	See Note 6 and Figure 7		3	50	μs
<sup>t</sup> pd(OLB)	Propagation delay time going out of loopback mode $\$$	$R_L = 3 k\Omega$ to 7 kΩ,	See Note 6 and Figure 7		3	50	μs
<sup>t</sup> pd(LB)	Propagation delay time in loopback mode $\P$	$R_L = 3 \text{ k}\Omega$ to 7 k $\Omega$ ,	See Note 6 and Figure 8		3	15	μs
<sup>t</sup> sk	Skew time in loopback mode	$R_L = 3 k\Omega$ to 7 kΩ,	See Note 6		4	10	μs

<sup>†</sup> All typical values are at  $T_A = 25^{\circ}C$ .

<sup>‡</sup>This is the delay between entering the loopback mode and when the data on the receiver output becomes valid.

§ This is the worst-case (rising or falling edges) total propagation delay between driver input and receiver output when in the loopback mode.

This is the magnitude of the difference between the propagation delay time of the rising and falling edges of tpd(LB).

NOTE 6: Skew time is the magnitude of the difference between tPHL and tPLH and is measured with a 0-to-3-V input pulse.



### **RECEIVER SECTION**

# electrical characteristics over full recommended ranges of supply voltages and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CO	NDITIONS	MIN	түр†	MAX	UNIT
VIT+	Positive-going input threshold voltage	See Figure 5		1.3	2	2.5	V
VIT-	Negative-going input threshold voltage	See Figure 5		0.5	1	1.7	V
V <sub>hys</sub>	Input hysteresis voltage ( $V_{IT+} - V_{IT-}$ )			0.5	1	1.5	V
V <sub>OH</sub> High-level output voltage		$V_{I} = -3 V$ or inputs open,	I <sub>OH</sub> = -20 μA	3.5			V
		$I_{OH} = -4 \text{ mA},$	See Note 7 and Figure 5	2.4			v
VOL	Low-level output voltage	I <sub>OL</sub> = 4 mA, See Figure 5	V <sub>I</sub> = 3 V,			0.4	V
IOS(H)	Short-circuit output current at high level	V <sub>OH</sub> = 0,	See Figure 4		-20	-60	mA
IOS(L)	Short-circuit output current at low level	$V_{OL} = V_{CC2},$	See Figure 4		20	60	mA
		$ V_{I}  \leq 25 V$		3			kO
'I	Input resistance	$ V_1  = 3 V \text{ to } 25 V$				7	K\$2

<sup>†</sup> All typical values are at  $T_A = 25^{\circ}C$ .

NOTE 7: If the inputs are left unconnected, the receiver interprets this as a low input and the receiver outputs will remain in the high state.

# switching characteristics over full recommended ranges of supply voltages and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low- to high-level output	Soo Eiguro 6		2	6	μs
<sup>t</sup> PHL	Propagation delay time, high- to low-level output	See Figure o		2	6	μs
<sup>t</sup> TLH	Transition time, low- to high-level output <sup>‡</sup>	Cu – 50 pE Soo Figuro 6		200	300	ns
<sup>t</sup> THL	Transition time, high- to low-level output <sup>‡</sup>	$C_{L} = 50  \text{pr}, \qquad \text{See Figure 6}$		50	300	ns
t <sub>sk</sub>	│ t <sub>PLH</sub> – t <sub>PHL</sub> │			0.1	1	μs
t <sub>W</sub>	Maximum pulse duration assumed to be noise§	Pulse amplitude = 5 V	1	2	4	μs

<sup>†</sup> All typical values are at  $T_A = 25^{\circ}C$ .

<sup>‡</sup> Transition times are measured between 10% and 90% points on output waveform.

§ The receiver will ignore any positive- or negative-going pulse whose duration is less than the minimum value of t<sub>w</sub> and accept any positive- or negative-going pulse whose duration is greater than the maximum value of t<sub>w</sub>.



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### PARAMETER MEASUREMENT INFORMATION



### Figure 1. Driver Test Circuit, V<sub>OH</sub>, V<sub>OL</sub>, I<sub>OS(L)</sub>, I<sub>OS(H)</sub>



Figure 2. Driver and Loopback Test Circuit, IIL, IIH



NOTES: A. The pulse generator has the following characteristics:  $t_W$  = 25 µs, PRR = 20 kHz,  $Z_O$  = 50  $\Omega$ .

B. C<sub>L</sub> includes probe and jig capacitance. C. Slew rate =  $\frac{6 V}{t_{f} \text{ or } t_{f}}$ 





### PARAMETER MEASUREMENT INFORMATION



### Figure 4. Receiver Test Circuit, IOS(H), IOS(L)



Figure 5. Receiver Test Circuit, V<sub>IT</sub>, V<sub>OL</sub>, V<sub>OH</sub>



NOTES: A. The pulse generator has the following characteristics:  $t_W = 25 \ \mu$ s, PRR = 20 kHz, Z<sub>O</sub> = 50  $\Omega$ . B. C<sub>L</sub> includes probe and jig capacitance.

### Figure 6. Receiver Propagation and Transition Times



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### PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics:  $t_W = 25 \ \mu s$ , PRR = 20 kHz,  $Z_O = 50 \ \Omega$ . B. CL includes probe and jig capacitance.



### Figure 7. Loopback Entry and Exit Propagation Times

NOTES: A. The pulse generator has the following characteristics:  $t_W = 25 \ \mu$ s, PRR = 20 kHz,  $Z_O = 50 \ \Omega$ . B. C<sub>1</sub> includes probe and jig capacitance.

### Figure 8. Loop Propagation Times in Loopback Mode



### **PRINCIPLES OF OPERATION**

In normal operation, the SN75186 acts as four independent drivers and receivers; the loopback mode is held off by keeping logic inputs  $\overline{LB}$  high. Taking a particular  $\overline{LB}$  input low activates the loopback mode in the corresponding driver/receiver pair. This causes the output from that driver to be fed back to the input of its receiver through dedicated internal loopback circuitry. Data from the receiver output can then be compared, by a communication system, with the data transmitted to the driver to determine if the functional operation of the driver and receiver together is correct.

In the loopback mode, external data at the input of the receiver is ignored and the driver does not transmit data onto the line. Extraneous data is prevented internally from being sent by the driver in the loopback mode by clamping its output to a level below the maximum interface voltage, -5 V, or the EIA/TIA-232-E marking state. Below this marking level, a reduced 1.5-V output amplitude is used at the driver output. This signal is detected by an on-chip loopback comparator and fed to the input stage of the receiver to complete the loop.

Line faults external to the SN75186 are detected in addition to device failures. These line faults include short circuits to ground and to external supply voltages that are greater than  $(V_{EE} + 7 V)$  and less than  $V_{EE}$  typically. For example, with  $V_{EE} = -12 V$ , line short circuits to voltages greater than -5 V and less than -12 V will be detected. The loopback mode should be entered only when the driver output is low, that is, the marking state of EIA/TIA-232-E. Loopback should not be entered when the driver output is in a high state as this may cause a low-level, nondamaging oscillation at the driver output.

When in the loopback mode, approximately 95% of the SN75186 circuit is functionally checked. There exists some low probability of fault mechanisms in circuitry not being checked in the loopback mode. To reduce the chances of undetected failure, the unchecked circuitry has been designed to be more robust than that within the loopback test loop. The areas where special attention has been paid are the receiver input potential divider and resistors, the driver output blocking diode (D1), and parts of the driver clamp circuit.

Protection of the SN75186 is achieved by means of driver output current limits and a thermal trip. Although this device can withstand  $\pm 30$  V at its receiver input, package thermal dissipation limitations have to be taken into consideration if more than one receiver is connected simultaneously. This is due to the possible dissipation in the 3-k $\Omega$  minimum input resistors, which is not under the control of the thermal trip. Although the supply current is higher in the loopback mode than in normal operation, the total power dissipation is not sufficient under normal worst-case conditions (of receiver input V<sub>I</sub> = 15 V + 10%, receiver output voltage = 2.4 V at 4 mA, driver load of 3 k $\Omega$ ) to cause the thermal limiting circuitry to trip.

If the SN75186 goes into thermal trip, the output of the driver goes to a high-impedance state and the receiver output is held in a logic-high marking state. Both driver and receiver outputs maintain a marking state and do not allow indeterminate conditions to exist.

The standards specify a minimum driver output resistance to ground of  $300 \Omega$  when the device is powered off. To fully comply with EIA/TIA-232-E power-off fault conditions, many drivers need diodes in series with each supply voltage to prevent reverse current flow and driver damage. The SN75186 overcomes this need by providing a high-impedance driver output of typically 5 k $\Omega$  under power-off conditions through the use of the equivalent of these series diodes in the driver output circuit.





2-Oct-2014

# PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins F	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
SN75186FN	OBSOLETE	PLCC	FN	28		TBD	Call TI	Call TI	0 to 70		
SN75186FNR	OBSOLETE	PLCC	FN	28		TBD	Call TI	Call TI	0 to 70		

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between

the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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# PACKAGE OPTION ADDENDUM

2-Oct-2014

# **MECHANICAL DATA**

MPLC004A - OCTOBER 1994

#### PLASTIC J-LEADED CHIP CARRIER

# FN (S-PQCC-J\*\*)



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-018



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